



# AT-LA500

## 500 MS/s USB Logic Analyzer 1.5GS/s with *GigaView* acquisition

### The Easiest and Cost-Effective Tool to Solve Your Toughest Digital Debugging Problems

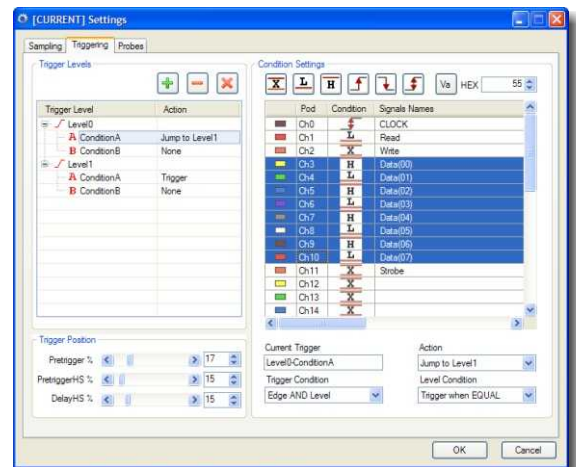
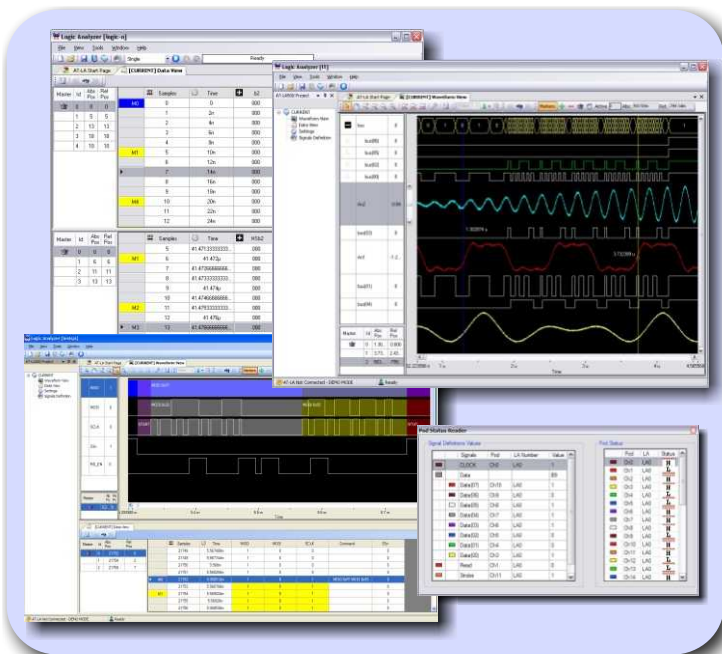
The AT-LA500 USB PC Based Logic Analyzer is the ideal solution to find and solve any digital testing issue. The AT-LA500 USB provides excellent performance and easy-to-use interface, combining the advantages of a compact size instrument with the flexibility of your PC for data management and visualization, all at affordable price. AT-LA500 can be also tightly integrated with most popular oscilloscopes to provide a complete high performance and low cost mixed signal test solution.

- 36 Channels @ 500MS/s
- GigaView: 36 Channels @ 1.5GS/s
- Up to 8 instruments linkable with AT-XSS bus
- 500 MHz Timing Analysis
- 200 MHz DDR / 100 MHz SDR State Analysis
- 31 trigger levels
- Serial Protocol Analysis with advanced trigger options
- Mixed signal Analysis (by oscilloscope integration)
- Up to 4 Million Samples on all channels
- Up to 130 min. of acquisition time
- 3 probe sets hot pluggable
- 4 programmable and independent thresholds on each instrument
- Digital Pattern Generator - Sampler (optional)



Powerful software allows to control advanced AT-LA500 functions using a user-friendly graphic interface:

- Easy to use instrument control and configuration
- Multiple display windows with cursors for simple measurements: Mixed Signal Waveform and Data View
- USB 2.0 interface (compatible 1.1) to transfer data to the PC within seconds
- LabView and C/C++ SDK (Software Development Kit)
- Windows 2000/XP OS



# Tech Specs:

Channels:	36 (up to 288 channels with AT-XSS bus)
Linkable instruments with AT-XSS bus:	Up to 8
Maximum sampling frequency:	500MSamples/s + 1.5GSamples/s with GigaView
Timing Analysis:	500MHz
State Analysis:	200MHz DDR / 100MHz SDR It is possible to sample on an external clock that comes from different combination of 4 dedicated inputs
Memory Depth:	Up to 4M Samples + 1k Samples @ 1.5GS/s
Trigger Settings:	Edge Condition: No edge, Rising Edge, Falling Edge, Both Edges on all channels Level Condition: Condition verified if the selected inputs are equal (or different) to the pattern that the user sets
Trigger Levels	31
Trigger Mode:	Edge AND Level; Edge OR Level; Edge THEN Level; Level THEN Edge; Always Trigger; Never Trigger; Manual Trigger
Dimensions (WxLxH):	17.3 x 27.3 x 6.7 cm
Weight:	700g
Interface:	USB 2.0 (compatible with USB 1.1)
Power Supply:	12 VDC

Probes Tech Specs:	Active Hi-Z Probe	ASP Probe	Passive Probe
Input Capacitance:	9pF	<10 pF	//
Input Resistance:	1.1MOhm	22kOhm	//
Maximum Toggle Rate:	80MHz	130MHz	100MHz
Linear Input Voltage Range:	-40V to +40V	-38V to +38V	0 to 5V
Threshold Voltage:	-40V to +40V in 20mV steps	-38V to +38V In 20mV steps	2V
Number of Thresholds:	2 programmable and independent	2 programmable and independent	1 Fixed

AT-LA500 is a test equipment instrument designed and made in Italy by Active Technologies. The company was founded in 2002 by a staff of engineers expert in semiconductor test equipment and instrumentation design.

Active Technologies is a supplier of innovative and avant-garde Automated Test Equipment and electronic instrumentation to world wide semiconductor company leaders.



如果你需要详细资料, 请联系我们: [sales@hkaco.com](mailto:sales@hkaco.com)

广州: 400 999 3848 | 上海: 021-31215998 | 北京: 010-57815068 | [www.hkaco.com](http://www.hkaco.com)